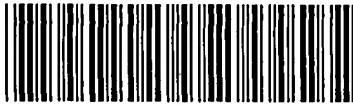


Search Notes

Application/Control No.

10/531,310

Examiner

Shin-Hon Chen

Applicant(s)/Patent under
Reexamination

FRENCH ET AL.

Art Unit

2131

SEARCHED

Class	Subclass	Date	Examiner
713	193	8/17/2007	S.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPAT, PGPUB, DERWENT, JPO ,EPO (BRS search - see search history)	8/17/2007	S.C.